

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|---|---|------------------|---------|------------------|
| S1 | 7 | "6162735" | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 14:59 |
| S2 | 2 | ("6288393").PN. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/08/01 16:23 |
| S3 | 3364 | 382/141-151.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 11:59 |
| S4 | 8041 | 438/6-17.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 13:23 |
| S5 | 45 | 438/6-17.ccls. and sem and fib and substrate | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 13:24 |
| S6 | 54 | 438/6-17.ccls. and sem and fib | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 13:35 |
| S7 | 1569 | 438/6-17.ccls. and substrate same remov\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 13:36 |
| S8 | 106 | 438/6-17.ccls. and substrate same remov\$3 and fail\$3 same detect\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 13:36 |
| S9 | 16 | gilfeather-glen.in. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 14:19 |
| S10 | 43 | "5430305" | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 14:24 |

| | | | | | | |
|-----|------|--|---|----|-----|------------------|
| S11 | 2 | ("4875209").PN. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 14:24 |
| S12 | 2 | ("5557559").PN. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 14:25 |
| S13 | 2 | ("6255124").PN. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 14:25 |
| S14 | 2 | ("6078183").PN. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/11/29 14:26 |
| S15 | 1081 | state and chang\$3 and circuit\$3 and defect and fail\$3 and substrate.cm. | US-PGPUB | OR | OFF | 2005/11/29 15:01 |
| S16 | 136 | state and chang\$3 and circuit\$3 and defect and fail\$3 and substrate and image\$2 and three and dimension\$3.cm. | US-PGPUB | OR | OFF | 2005/11/29 15:01 |
| S17 | 27 | state and chang\$3 and circuit\$3 and defect and fail\$3 and substrate and image\$2 and three and dimension\$3 and die.cm. | US-PGPUB | OR | OFF | 2005/11/29 15:01 |

Day : Tuesday
Date: 11/29/2005

PALM INTRANET

Time: 13:38:41

Inventor Name Search Result

Your Search was:

Last Name = GILFEATHER

First Name = GLEN

| Application# | Patent# | Status | Date Filed | Title | Inventor Name |
|--------------------------|-------------------------|--------|------------|--|------------------|
| 07050979 | 4819047 | 150 | 05/15/1987 | PROTECTION SYSTEM FOR CMOS INTEGRATED CIRCUITS | GILFEATHER, GLEN |
| 07212282 | 4870530 | 150 | 06/27/1988 | ELECTROSTATIC DISCHARGE PROTECTION CIRCUITRY FOR ANY TWO EXTERNAL PINS OF AN I.C. PACKAGE | GILFEATHER, GLEN |
| 08988868 | 5972725 | 250 | 12/11/1997 | DEVICE ANALYSIS FOR FACE DOWN CHIP | GILFEATHER, GLEN |
| 09050531 | 6069366 | 150 | 03/30/1998 | ENDPOINT DETECTION FOR THINNING OF SILICON OF A FLIP CHIP BONDED INTEGRATED CIRCUIT | GILFEATHER, GLEN |
| 09074627 | 6171944 | 250 | 05/07/1998 | A METHOD FOR BRINGING UP LOWER LEVEL METAL NODES OF MULTI-LAYERED INTEGRATED CIRCUITS FOR SIGNAL ACQUISITION | GILFEATHER, GLEN |
| 09383790 | 6372627 | 150 | 08/26/1999 | ARRANGEMENT AND METHOD FOR CHARACTERIZATION OF FOCUSED-ION-BEAM INSULATOR DEPOSITION. | GILFEATHER, GLEN |
| 09409089 | 6352871 | 150 | 09/30/1999 | PROBE GRID FOR INTEGRATED CIRCUIT EXCITATION | GILFEATHER, GLEN |
| 09409982 | 6455334 | 150 | 09/30/1999 | PROBE GRID FOR INTEGRATED CIRCUIT ANALYSIS | GILFEATHER, GLEN |
| 09578195 | 6285036 | 150 | 05/24/2000 | Endpoint detection for thinning of silicon of a flip chip bonded integrated circuit | GILFEATHER, GLEN |
| | | | | | |

| | | | | | |
|-----------------|----------------|-----|------------|---|--------------------------|
| <u>09580716</u> | <u>6469529</u> | 150 | 05/30/2000 | TIME-RESOLVED EMISSION MICROSCOPY SYSTEM | GILFEATHER, GLEN |
| <u>09826576</u> | <u>6518661</u> | 150 | 04/05/2001 | APPARATUS FOR METAL STACK THERMAL MANAGEMENT IN SEMICONDUCTOR DEVICES | GILFEATHER, GLEN |
| <u>09833247</u> | Not Issued | 71 | 04/11/2001 | Three-dimensional tomography | GILFEATHER, GLEN |
| <u>09833250</u> | <u>6566888</u> | 150 | 04/11/2001 | REPAIR OF RESISTIVE ELECTRICAL CONNECTIONS IN AN INTEGRATED CIRCUIT | GILFEATHER, GLEN |
| <u>10261390</u> | <u>6897664</u> | 150 | 09/30/2002 | LASER BEAM INDUCED PHENOMENA DETECTION | GILFEATHER, GLEN |
| <u>10324328</u> | <u>6833718</u> | 150 | 12/20/2002 | PHOTON BEACON | GILFEATHER, GLEN |
| <u>60198365</u> | Not Issued | 159 | 04/19/2000 | Semiconductor analysis arrangement and analysis therefor | GILFEATHER, GLEN P |
| <u>09838667</u> | Not Issued | 161 | 04/19/2001 | Semiconductor analysis using thermal control | GILFEATHER, GLEN P. |
| <u>09838671</u> | <u>6700659</u> | 150 | 04/19/2001 | SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR | GILFEATHER, GLEN P. |
| <u>09838672</u> | <u>6635839</u> | 150 | 04/19/2001 | SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR | GILFEATHER, GLEN P. |
| <u>09838717</u> | <u>6844928</u> | 150 | 04/19/2001 | FIBER OPTIC SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR | GILFEATHER, GLEN P. |
| <u>09887638</u> | <u>6716683</u> | 150 | 06/22/2001 | OPTICAL ANALYSIS FOR SOI INTEGRATED CIRCUITS | GILFEATHER, GLEN P. |
| <u>09694523</u> | <u>6661246</u> | 150 | 10/23/2000 | CONSTANT-CURRENT VDDQ TESTING OF INTEGRATED CIRCUITS | GILFEATHER, GLEN PATRICK |

Inventor Search Completed: No Records to Display.

Search Another: Inventor

| | | |
|---|-----------------------------------|---------------------------------------|
| Last Name | First Name | |
| <input type="text" value="GILFEATHER"/> | <input type="text" value="GLEN"/> | <input type="button" value="Search"/> |

To go back use Back button on your browser toolbar.

Back to [PALM](#) | [ASSIGNMENT](#) | [OASIS](#) | [Home page](#)

Day : Tuesday
Date: 11/29/2005


PALM INTRANET

Time: 13:06:14

Inventor Name Search Result

Your Search was:

Last Name = BRUCE

First Name = VICTORIA

| Application# | Patent# | Status | Date Filed | Title | Inventor Name |
|-----------------|---------------|--------|------------|--|----------------------|
| <u>09247001</u> | 6417068 | 150 | 02/08/1999 | SEMICONDUCTOR DEVICE NAVIGATION USING LASER SCRIBING | BRUCE, VICTORIA |
| <u>09273954</u> | Not Issued | 161 | 03/22/1999 | MARKER IMPLANTATION FOR IMPROVED END- POINTDETECTION | BRUCE, VICTORIA |
| <u>09838667</u> | Not Issued | 161 | 04/19/2001 | Semiconductor analysis using thermal control | BRUCE, VICTORIA |
| <u>09838671</u> | 6700659 | 150 | 04/19/2001 | SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR | BRUCE, VICTORIA |
| <u>09838672</u> | 6635839 | 150 | 04/19/2001 | SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR | BRUCE, VICTORIA |
| <u>09838717</u> | 6844928 | 150 | 04/19/2001 | FIBER OPTIC SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR | BRUCE, VICTORIA |
| <u>60198365</u> | Not Issued | 159 | 04/19/2000 | Semiconductor analysis arrangement and analysis therefor | BRUCE, VICTORIA |
| <u>09385774</u> | 6410349 | 150 | 08/30/1999 | INTERNAL ANTI- REFLECTIVE COATING FOR INTERFERENCE REDUCTION | BRUCE, VICTORIA J |
| <u>09052221</u> | 6107107 | 150 | 03/31/1998 | ANALYZING AN ELECTRONIC CIRCUIT FORMED UPON A FRONTSIDE SURFACE OF A SEMICONDUCTOR SUBSTRATE BY DETECTING RADIATION EXITING A BACKSIDE SURFACE COATED WITH AN ANTIREFLECTIVE MATERIAL | BRUCE, VICTORIA J |

| | | | | | |
|-----------------|----------------|-----|------------|---|--------------------|
| <u>09578195</u> | <u>6285036</u> | 150 | 05/24/2000 | Endpoint detection for thinning of silicon of a flip chip bonded integrated circuit | BRUCE, VICTORIA J. |
| <u>09586505</u> | <u>6549022</u> | 150 | 06/02/2000 | APPARATUS AND METHOD FOR ANALYZING FUNCTIONAL FAILURES IN INTEGRATED CIRCUITS | BRUCE, VICTORIA J. |
| <u>09586518</u> | Not Issued | 95 | 06/02/2000 | RESISTIVITY ANALYSIS | BRUCE, VICTORIA J. |
| <u>09586572</u> | <u>6546513</u> | 150 | 06/02/2000 | DATA PROCESSING DEVICE TEST APPARATUS AND METHOD THEREFOR | BRUCE, VICTORIA J. |
| <u>09654823</u> | <u>6375347</u> | 150 | 09/05/2000 | METHOD FOR LASER SCANNING FLIP-CHIP INTEGRATED CIRCUITS | BRUCE, VICTORIA J. |
| <u>09766472</u> | Not Issued | 163 | 01/19/2001 | Semiconductor die analysis using above band-gap energy | BRUCE, VICTORIA J. |
| <u>09833247</u> | Not Issued | 71 | 04/11/2001 | Three-dimensional tomography | BRUCE, VICTORIA J. |
| <u>10084100</u> | <u>6617862</u> | 150 | 02/27/2002 | LASER INTRUSIVE TECHNIQUE FOR LOCATING SPECIFIC INTEGRATED CIRCUIT CURRENT PATHS | BRUCE, VICTORIA J. |
| <u>10164739</u> | <u>6870379</u> | 150 | 06/06/2002 | INDIRECT STIMULATION OF AN INTEGRATED CIRCUIT DIE | BRUCE, VICTORIA J. |
| <u>60307995</u> | Not Issued | 159 | 07/26/2001 | Indirect stimulation of an integrated circuit die | BRUCE, VICTORIA J. |
| <u>07826992</u> | <u>5301006</u> | 150 | 01/28/1992 | EMISSION MICROSCOPE | BRUCE, VICTORIA J. |
| <u>07827732</u> | Not Issued | 166 | 01/28/1992 | ENERGY RESOLVED EMISSION MICROSCOPY SYSTEM AND METHOD | BRUCE, VICTORIA J. |
| <u>08104245</u> | Not Issued | 166 | 08/09/1993 | ENERGY RESOLVED EMISSION MICROSCOPY SYSTEM AND METHOD | BRUCE, VICTORIA J. |
| <u>08350381</u> | <u>5661520</u> | 250 | 12/05/1994 | ENERGY RESOLVED EMISSION MICROSCOPY SYSTEM AND METHOD | BRUCE, VICTORIA J. |
| <u>09050531</u> | <u>6069366</u> | 150 | 03/30/1998 | ENDPOINT DETECTION FOR THINNING OF SILICON OF A FLIP CHIP BONDED INTEGRATED CIRCUIT | BRUCE, VICTORIA J. |
| <u>09187314</u> | <u>6146014</u> | 250 | 11/04/1998 | METHOD FOR LASER | BRUCE, VICTORIA |

| | | | | | |
|-----------------|----------------|-----|------------|--|-------------------------|
| | | | | SCANNING FLIP-CHIP INTEGRATED CIRCUITS | J. |
| <u>09383725</u> | <u>6350982</u> | 150 | 08/26/1999 | INDUCEMENT AND DETECTION OF LATCH-UP USING A LASER SCANNING MICROSCOPE | BRUCE, VICTORIA J. |
| <u>09383733</u> | <u>6348364</u> | 150 | 08/26/1999 | NAVIGATION USING 3-D DETECTABLE PATTERN | BRUCE, VICTORIA J. |
| <u>09383782</u> | <u>6545490</u> | 150 | 08/26/1999 | TRENCH-FILLED PROBE POINT FOR A SEMICONDUCTOR DEVICE | BRUCE, VICTORIA J. |
| <u>09383793</u> | Not Issued | 161 | 08/26/1999 | PROBE REGION METHOD AND APPARATUS | BRUCE, VICTORIA J. |
| <u>09409088</u> | <u>6483327</u> | 150 | 09/30/1999 | QUADRANT AVALANCHE PHOTODIODE TIME- RESOLVED DETECTION | BRUCE, VICTORIA J. |
| <u>10209844</u> | <u>6714294</u> | 150 | 07/31/2002 | DE BROGLIE MICROSCOPE | BRUCE, VICTORIA JEAN |
| <u>09166266</u> | <u>6300148</u> | 250 | 10/05/1998 | SEMICONDUCTOR STRUCTURE WITH A BACKSIDE PROTECTIVE LAYER AND BACKSIDE PROBES AND A METHOD FOR CONSTRUCTING THE STRUCTURE | BRUCE, VICTORIA JEAN |
| <u>09166833</u> | Not Issued | 163 | 10/05/1998 | ENDPOINT DETECTION FOR THINNING OF A FLIP CHIP BONDED INTEGRATED CIRCUIT | BRUCE, VICTORIA JEAN |
| <u>09249367</u> | <u>6210981</u> | 150 | 02/12/1999 | METHOD FOR ETCHING A FLIP CHIP USING SECONDARY PARTICLE EMISSIONS TO DETECT THE ETCH END - POINT | BRUCE, VICTORIA JEAN |

Inventor Search Completed: No Records to Display.

| | | | |
|---------------------------------|------------------------------------|---------------------------------------|---------------------------------------|
| | Last Name | First Name | |
| Search Another: Inventor | <input type="text" value="BRUCE"/> | <input type="text" value="VICTORIA"/> | <input type="button" value="Search"/> |

To go back use Back button on your browser toolbar.

Back to [PALM](#) | [ASSIGNMENT](#) | [OASIS](#) | [Home page](#)

Day : Tuesday
Date: 11/29/2005


PALM INTRANET

Time: 12:09:12

Inventor Name Search Result

Your Search was:

Last Name = BRUCE

First Name = MICHAEL

| Application# | Patent# | Status | Date Filed | Title | Inventor Name |
|-----------------|----------------|--------|------------|---|---------------------------------|
| <u>60162125</u> | Not Issued | 159 | 10/29/1999 | SYSTEM AND METHOD FOR DEFINING AUTOMATED ACCESS PROTOCOLS FOR ELECTRONIC TRANSACTIONS WITH MULTIPLE MERCHANTS | BRUCE SR., MICHAEL GEORGE |
| <u>09259542</u> | <u>6177989</u> | 150 | 03/01/1999 | LASER INDUCED CURRENT FOR SEMICONDUCTOR DEFECT DETECTION | BRUCE, MICHAEL |
| <u>09838667</u> | Not Issued | 161 | 04/19/2001 | Semiconductor analysis using thermal control | BRUCE, MICHAEL |
| <u>09838671</u> | <u>6700659</u> | 150 | 04/19/2001 | SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR | BRUCE, MICHAEL |
| <u>09838672</u> | <u>6635839</u> | 150 | 04/19/2001 | SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR | BRUCE, MICHAEL |
| <u>09838717</u> | <u>6844928</u> | 150 | 04/19/2001 | FIBER OPTIC SEMICONDUCTOR ANALYSIS ARRANGEMENT AND METHOD THEREFOR | BRUCE, MICHAEL |
| <u>10147317</u> | Not Issued | 41 | 05/17/2002 | Examining chemical reactions | BRUCE, MICHAEL |
| <u>10231560</u> | Not Issued | 94 | 08/30/2002 | THERMALLY CONDUCTIVE INTEGRATED CIRCUIT MOUNTING STRUCTURES | BRUCE, MICHAEL |
| <u>10261390</u> | <u>6897664</u> | 150 | 09/30/2002 | LASER BEAM INDUCED PHENOMENA DETECTION | BRUCE, MICHAEL |
| <u>60035667</u> | Not Issued | 159 | 01/21/1997 | PREDICTIVE COLLISION SENSING FOR DEPLOYING ACTIVE SAFETY SYSTEMS FOR AUTOMOBILE | BRUCE, MICHAEL |
| <u>60198365</u> | Not | 159 | 04/19/2000 | Semiconductor analysis | BRUCE, MICHAEL |

| | Issued | | | arrangement and analysis therefor | |
|-----------------|----------------|-----|------------|--|-----------------------|
| <u>09003672</u> | <u>6056079</u> | 150 | 01/07/1998 | AUTOMOTIVE SEAT WEIGHT SENSING SYSTEM | BRUCE, MICHAEL P. |
| <u>06920178</u> | Not Issued | 161 | 10/17/1986 | TAMPER PROOF LIQUID STAIN SEAL | BRUCE, MICHAEL B. |
| <u>09698072</u> | Not Issued | 71 | 10/30/2000 | System and method of aggregate electronic transactions with multiple sources | BRUCE, MICHAEL GEORGE |
| <u>09698073</u> | Not Issued | 160 | 10/30/2000 | System and method of data exchange for electronic transactions with multiple sources | BRUCE, MICHAEL GEORGE |
| <u>09917810</u> | Not Issued | 41 | 07/31/2001 | System and method of data exchange for electronic transactions with multiple sources | BRUCE, MICHAEL GEORGE |
| <u>60420374</u> | Not Issued | 159 | 10/22/2002 | Programmable alarm audio device | BRUCE, MICHAEL L. |
| <u>08841521</u> | <u>6005958</u> | 150 | 04/23/1997 | OCCUPANT TYPE AND POSITION DETECTION SYSTEM | BRUCE, MICHAEL P. |
| <u>60256777</u> | Not Issued | 159 | 12/18/2000 | Self-powered crash sensing module | BRUCE, MICHAEL P. |
| <u>08878090</u> | <u>6070113</u> | 150 | 06/18/1997 | HYBRID VEHICLE CRASH DISCRIMINATION SYSTEM | BRUCE, MICHAEL P. |
| <u>09009035</u> | <u>6085151</u> | 150 | 01/20/1998 | PREDICTIVE COLLISION SENSING SYSTEM | BRUCE, MICHAEL P. |
| <u>09018256</u> | <u>5979586</u> | 150 | 02/04/1998 | VEHICLE COLLISION WARNING SYSTEM | BRUCE, MICHAEL P. |
| <u>09368251</u> | <u>6198998</u> | 250 | 08/03/1999 | OCCUPANT TYPE AND POSITION DETECTION SYSTEM | BRUCE, MICHAEL P. |
| <u>60020489</u> | Not Issued | 159 | 06/21/1996 | HYBRID VEHICLE CRASH DISCRIMINATION SYSTEM | BRUCE, MICHAEL P. |
| <u>60034018</u> | Not Issued | 159 | 01/08/1997 | AUTOMOTIVE SEAT WEIGHT SENSING SYSTEM | BRUCE, MICHAEL P. |
| <u>60037299</u> | Not Issued | 159 | 02/05/1997 | WARNING SYSTEM FOR VEHICLE COLLISION PREDICTION | BRUCE, MICHAEL P. |
| <u>09520597</u> | <u>6488405</u> | 150 | 03/08/2000 | FLIP CHIP DEFECT ANALYSIS USING LIQUID CRYSTAL | BRUCE, MICHAEL R. |
| <u>09011080</u> | Not Issued | 161 | 01/27/1998 | CHOCOLATE WITH RAISED DESIGN | BRUCE, MICHAEL R. |

| | | | | | |
|-----------------|----------------|-----|------------|---|-------------------|
| <u>09580716</u> | <u>6469529</u> | 150 | 05/30/2000 | TIME-RESOLVED EMISSION MICROSCOPY SYSTEM | BRUCE, MICHAEL R. |
| <u>09583617</u> | Not Issued | 121 | 05/31/2000 | Electrical probing of soi circuits | BRUCE, MICHAEL R. |
| <u>09586505</u> | <u>6549022</u> | 150 | 06/02/2000 | APPARATUS AND METHOD FOR ANALYZING FUNCTIONAL FAILURES IN INTEGRATED CIRCUITS | BRUCE, MICHAEL R. |
| <u>09586518</u> | Not Issued | 95 | 06/02/2000 | RESISTIVITY ANALYSIS | BRUCE, MICHAEL R. |
| <u>09586572</u> | <u>6546513</u> | 150 | 06/02/2000 | DATA PROCESSING DEVICE TEST APPARATUS AND METHOD THEREFOR | BRUCE, MICHAEL R. |
| <u>09613667</u> | <u>6500699</u> | 150 | 07/11/2000 | TESTING OF SOI DIE | BRUCE, MICHAEL R. |
| <u>09654823</u> | <u>6375347</u> | 150 | 09/05/2000 | METHOD FOR LASER SCANNING FLIP-CHIP INTEGRATED CIRCUITS | BRUCE, MICHAEL R. |
| <u>09750454</u> | Not Issued | 168 | 12/28/2000 | Nanomachining method for integrated circuits | BRUCE, MICHAEL R. |
| <u>09750644</u> | Not Issued | 160 | 12/28/2000 | Nanomachining of integrated circuits | BRUCE, MICHAEL R. |
| <u>09750650</u> | Not Issued | 168 | 12/28/2000 | Optical analysis of integrated circuits | BRUCE, MICHAEL R. |
| <u>09750651</u> | Not Issued | 168 | 12/28/2000 | Circuit access and analysis for a SOI flip-chip die | BRUCE, MICHAEL R. |
| <u>09751097</u> | Not Issued | 161 | 12/28/2000 | SOI die analysis of circuitry logic states via coupling through the insulator | BRUCE, MICHAEL R. |
| <u>09755005</u> | <u>6403388</u> | 150 | 01/05/2001 | NANOMACHINING METHOD FOR INTEGRATED CIRCUITS | BRUCE, MICHAEL R. |
| <u>09755008</u> | Not Issued | 121 | 01/05/2001 | Optical analysis of integrated circuits | BRUCE, MICHAEL R. |
| <u>09755011</u> | <u>6472760</u> | 150 | 01/05/2001 | NANOMACHINING OF INTEGRATED CIRCUITS | BRUCE, MICHAEL R. |
| <u>09755012</u> | <u>6621281</u> | 150 | 01/05/2001 | SOI DIE ANALYSIS OF CIRCUITRY LOGIC STATES VIA COUPLING THROUGH THE INSULATOR | BRUCE, MICHAEL R. |
| <u>09755013</u> | <u>6448095</u> | 150 | 01/05/2001 | CIRCUIT ACCESS AND ANALYSIS FOR A SOI FLIP-CHIP DIE | BRUCE, MICHAEL R. |
| <u>09766472</u> | Not Issued | 163 | 01/19/2001 | Semiconductor die analysis using above band-gap energy | BRUCE, MICHAEL R. |

| | | | | | |
|--------------------------|---------------|-----|------------|--|----------------------|
| 09833247 | Not Issued | 71 | 04/11/2001 | Three-dimensional tomography | BRUCE, MICHAEL R. |
| 09833250 | 6566888 | 150 | 04/11/2001 | REPAIR OF RESISTIVE ELECTRICAL CONNECTIONS IN AN INTEGRATED CIRCUIT | BRUCE, MICHAEL R. |
| 09864656 | 6448096 | 150 | 05/23/2001 | ATOMIC FORCE MICROSCOPY AND SIGNAL ACQUISITION VIA BURIED INSULATOR | BRUCE, MICHAEL R. |
| 09864665 | 6621288 | 150 | 05/23/2001 | TIMING MARGIN ALTERATION VIA THE INSULATOR OF A SOI DIE | BRUCE, MICHAEL R. |

[Search and Display More Records.](#)

Search Another: Inventor

| Last Name | First Name | |
|------------------------------------|--------------------------------------|---------------------------------------|
| <input type="text" value="BRUCE"/> | <input type="text" value="MICHAEL"/> | <input type="button" value="Search"/> |

To go back use Back button on your browser toolbar.

Back to [PALM](#) | [ASSIGNMENT](#) | [OASIS](#) | [Home page](#)

[Sign in](#)
[Web](#)
[Images](#)
[Groups](#)
[News](#)
[Froogle](#)
[Local](#)
[New!](#)
[more »](#)

defect suspect circuit, die, fib, sem

Search

[Advanced Search](#)
[Preferences](#)
WebResults 1 - 10 of about 293 for **defect suspect circuit, die, fib, sem**. (0.25 seconds)

Tip: Save time by hitting the return key instead of clicking on "search"

Sponsored Links

[PDF] Identification of an I Failure Mechanism Using a Variety of Front ...File Format: PDF/Adobe Acrobat - [View as HTML](#)Dual Beam (**FIB/SEM**) Cross-sections. In a dual beam **FIB/SEM** successive precision **FIB** cross- ... the **die** is grounded via the **SEM** stub and the chip is "biased" ...www.matrixsemi.com/technology/[documents/ISTFAConference_S7_V4.pdf](#) - [Similar pages](#)**Sem Specialty Paints**Autobody Depot carries the complete **Sem** Product Line at wholesale price www.AutoBodyDepot.net**[PDF] Computer-Aided Fault to Defect Mapping (CAFDM) for Defect Diagnosis**File Format: PDF/Adobe Acrobat - [View as HTML](#)Sample **Die**. for FA. Electrical. Test Data. Inline. Data. **FIB**, EDX etc. Physical ... **SEM** Isolation. of **Defects**. Run Diagnostic. Test. **Suspect Nets** ...faculty.cs.tamu.edu/walker/pubs/stanojevic00.pdf - [Similar pages](#)**IC Failure Analysis: The Importance of Test and Diagnostics**We can localize faults to the nearest logic block or **circuit** net, or in some cases directly to the responsible **defect's** physical location. ...doi.ieeeecomputersociety.org/10.1109/54.606001 - [Similar pages](#)**[PDF] Computer-Aided Fault to Defect Mapping (CAFDM) for Defect Diagnosis**

File Format: PDF/Adobe Acrobat

required to reduce **SEM** search time. The small **suspect** list ... Sample **Die**. for FA.Electrical. Test Data. Inline. Data. **FIB**, EDX etc. Physical ...doi.ieeeecomputersociety.org/10.1109/TEST.2000.894269 - [Similar pages](#)[[More results from doi.ieeeecomputersociety.org](#)]**[PDF] In-Line Defect Reduction From a Historical Perspective and Its ...**

File Format: PDF/Adobe Acrobat

suspect die areas [1]. Visual inspections of memory device ... a **defect** sectioned by **FIB**.

The convenience of obtaining cross- ...

ieeexplore.ieee.org/iel5/66/29734/01353320.pdf?arnumber=1353320 - [Similar pages](#)**[PDF] Computer-aided fault to defect mapping [CAFDM] for defect ...**

File Format: PDF/Adobe Acrobat

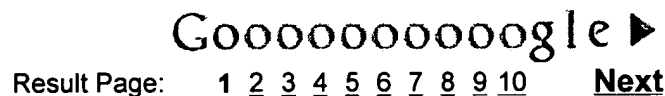
Sample **Die**. for FA. Baseline. Goal. 30%. 4 5 %. No. Yes. No. Yes. 80-95%. 90-99%. Days.Hours. Run Diagnostic. **Suspect Nets**. Design. &Test. **FIB**, EDX etc. ...ieeexplore.ieee.org/iel5/7183/19342/00894269.pdf?arnumber=894269 - [Similar pages](#)**[PDF] Researching for an Industrial Competitive Edge**File Format: PDF/Adobe Acrobat - [View as HTML](#)**circuit** on FR-4 are confirmed by **FIB-SEM** microscopy and I- ... WLP ICs and ensure **defect-free** operation of individual packages. in the field. ...www.ime.a-star.edu.sg/07newspub/newslink/Jan_05/main.pdf - [Similar pages](#)**[PDF] Assembly Analytical Forum Analytical Tool Roadmap White Paper**File Format: PDF/Adobe Acrobat - [View as HTML](#)

As package complexity is increased, analysis and repair analogous to die-level FIB circuit edit. and repair will be needed at the package level. ...
www.semtech.org/docubase/document/4532atr.pdf - [Similar pages](#)

Semiconductor International - Trends in Structural Defect Analysis ...
 ... able to see down into a **circuit** through several ... From a **defect** analysis and process control perspective ... sampling, or because they appear **suspect** during inspection ...
[www.reedelectronicsgroup.com/semiconductor/ article/CA92536?pubdate=7%2F1%2F2001](http://www.reedelectronicsgroup.com/semiconductor/article/CA92536?pubdate=7%2F1%2F2001)
 - Supplemental Result - [Similar pages](#)

S/390 G5 CMOS microprocessor diagnostics
Figure 9(b) shows the **SEM** image of the **defect**. ... **FIB** may be used to expose otherwise hidden **circuit** components for contact or contactless probing or may ...
www.research.ibm.com/journal/rd/435/song.html - 74k - [Cached](#) - [Similar pages](#)

Try searching for defect suspect circuit, die, fib, sem on Google Book Search



Free! Instantly find your email, files, media and web history. [Download now.](#)

defect suspect circuit, die, fib, sem Search

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2005 Google

[Search Session History](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Edit an existing query or
compose a new query in the
Search Query Display.

Tue, 29 Nov 2005, 12:54:17 PM EST

Search Query Display

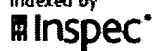
Select a search number (#)
to:

- Add a query to the Search Query Display
- Combine search queries using AND, OR, or NOT
- Delete a search
- Run a search

Recent Search Queries

- #1 (((suspected defect, resistive defect, sem, fib)<in>metadata))
<and> (pyr >= 1950 <and> pyr <= 2001)
- #2 (((defect, resistive defect, sem, fib)<in>metadata)) <and> (pyr
>= 1950 <and> pyr <= 2001)
- #3 (((defect suspect circuitry, resistive defect, sem, fib)
<in>metadata)) <and> (pyr >= 1950 <and> pyr <= 2001)
- #4 (((state changing, defect suspect circuitry, resistive defect, sem,
fib)<in>metadata)) <and> (pyr >= 1950 <and> pyr <= 2001)
- #5 (((state changing, defect suspect circuit, resistive defect, sem,
fib)<in>metadata)) <and> (pyr >= 1950 <and> pyr <= 2001)

Indexed by

[Help](#) [Contact Us](#) [Privacy & :](#)

© Copyright 2005 IEEE -